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TEST REPORT

Application No.: HKEM2101000004AT

Applicant: VTECH TELECOMMUNICATIONS LTD

Address of Applicant: 23/F., BLOCK 1, TAI PING INDUSTRIAL CENTRE, NO. 57 TING KOK

ROAD, TAI PO, N.T., Hong Kong

Equipment Under Test (EUT):

EUT Name: Pan & Tilt Monitor

Model No.: LF920HD BU, LF920-2HD BU, LF920-abHD BU, LF920-0HD BU, LF920-

0bHD BU

Additional Model: Please refer to section 2 of this report which indicates which item was

actually tested and which were electrically identical.

FCC ID: EW780-2367-00 IC: 1135B-80236700 HVIN: 35-400347BU

47 CFR Part 1.1307; 47 CFR Part 2.1093 Standard(s):

KDB447498D01 General RF Exposure Guidance v06

RSS102 Issue 5 March 2015

2021-01-05 **Date of Receipt:**

2021-01-06 to 2021-01-13 Date of Test:

2021-01-14 Date of Issue:

Test Result: Pass*



Law Man Kit **EMC Manager**

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^{*} In the configuration tested, the EUT complied with the standards specified above.



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	Revision Record						
Version	Chapter	Date	Modifier	Remark			
01		2021-01-14		Original			

Authorized for issue by:		
	Lev Xn.	
	Leo Xu /Project Engineer	Date: 2021-01-14
	Law	
	Law Man Kit	
	/Reviewer	Date: 2021-01-14



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2 Test Summary

Radio Spectrum Te	chnical Requirement			
Item	Standard	Method	Requirement	Result
RF Exposure	47 CFR Part 1.1307, 47 CFR Part 2.1093, KDB 447498 D01	KDB447498D01	KDB447498D01	PASS
RF Exposure	RSS102 Issue 5	RSS-102 Section 2.5.1	RSS102 Issue 5	PASS

Declaration of EUT Family Grouping:

Item no:

LF920HD BU, LF920-2HD BU, LF920-abHD BU, LF920-0HD BU, LF920-0bHD BU

a=any alphanumeric character or blank is presenting number of baby unit.

b= any alphanumeric character or blank is presenting color option

According to the confirmation from the applicant, the above models are identical in all electrical aspects in relating to the circuit design, PCB layout, electrical components used, internal wiring and functions. The differences are only the model/item No, color and decorations.

Therefore, only the model LF920HD BU was tested in this report.

Abbreviation:

Tx: In this whole report Tx (or tx) means Transmitter.

Rx: In this whole report Rx (or rx) means Receiver.

RF: In this whole report RF means Radiated Frequency.

CH: In this whole report CH means channel.

Volt: In this whole report Volt means Voltage.

Temp: In this whole report Temp means Temperature.

Humid: In this whole report Humid means humidity.

Press: In this whole report Press means Pressure.

N/A: In this whole report not application.



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4 General Information

4.1 Details of E.U.T.

50.0	
Power supply:	Adaptor model: VT07EUS05150
	Input: AC 100-240V, 50/60Hz, 0.5A
	Output: DC 5V, 1.5A
Test voltage:	AC 120V
Cable:	Power Cable: 200cm unshielded 2 wires DC cable
Antenna Gain:	2 dBi
Antenna Type:	Integral antenna
Channel Spacing:	3MHz
Modulation Type:	GFSK
Number of Channels:	24
Operation Frequency:	2405MHz to 2475MHz
Spectrum Spread Technology:	Frequency Hopping Spread Spectrum (FHSS)
Series number:	A1
Hardware Version:	V001
Software Version:	V0.0.0.7
	Remark: Power level setting was not adjustable and fixed default through SW Version.



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Frequency List

Channel Number	TX Freq (MHz)	Channel Number	TX Freq (MHz)
1	2406	13	2442
2	2409	14	2445
3	2412	15	2448
4	2415	16	2451
5	2418	17	2454
6	2421	18	2457
7	2424	19	2460
8	2427	20	2463
9	2430	21	2466
10	2433	22	2469
11	2436	23	2472
12	2439	24	2475

Remark: 1. Operation channel is only 16 within total channel 24.

2. Testing Channels are highlighted in **bold**.

4.2 Description of Support Units

The EUT has been tested with corresponding accessories as below: Supplied by client

Description	Manufacturer	Model No.	SN/Certificate NO
UART Test board	N/A	MX3232	N/A
Test Software	MicroRidge System	Version 3.0.0.108	N/A

Supplied by SGS:

Description	Manufacturer	Model No.	SN/Certificate NO
NoteBook (EMC4)	Dell	P75F	N/A



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4.3 Test Location

All tests were performed at:

SGS Hong Kong Limited

Unit 2 and 3, G/F, Block A, Po Lung Centre,

11 Wang Chiu Road, Kowloon Bay, Kowloon, Hong Kong

Tel: +852 2305 2570 Fax: +852 2756 4480

No tests were sub-contracted.

4.4 Test Facility

The test facility is recognized, certified, or accredited by the following organizations:

· HOKLAS (Lab Code: 009)

SGS Hong Kong Limited has been accepted by HKAS Executive, on the recommendation of the Accreditation Advisory Board, as a HOKLAS Accredited Laboratory, this laboratory meets the requirements of ISO/IEC 17025:2017 an it has been accredited for performing specific test as listed in the scope of accreditation within the test category of Electrical and Electronic Products.

• IAS Accreditation (Lab Code: TL-187)

SGS Hong Kong Limited has met the requirements of AC89, IAS Accreditation Criteria for Testing Laboratories, and has demonstrated compliance with ISO/IEC Standard 17025:2017, General requirements for the competence of testing and calibration laboratories. This organization is accredited to provide the services specified in the scope of accreditation maintained on the IAS website (www.iasonline.org).

The report must not be used by the client to claim product certification, approval, or endorsement by IAS, NIST, or any agency of the Federal Government.

• FCC Recognized Accredited Test Firm(CAB Registration No.: 514599)

SGS Hong Kong Limited has been accredited and fully described in a report filed with the (FCC) Federal Communications Commission. The acceptance letter from the FCC is maintained in our files. Designation Number: HK0015, Test Firm Registration Number: 514599.

• Industry Canada (Site Registration No.: 26103; CAB Identifier No.: HK0015)

SGS Hong Kong Limited has been recognized by Department of Innovation, Science and Economic Development (ISED) Canada as a wireless testing laboratory. The acceptance letter from the ISED is maintained in our files. CAB Identifier No: HK0015, Site Registration Number: 26103.

4.5 Deviation from Standards

None

4.6 Abnormalities from Standard Conditions

None



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5 Radio Spectrum Technical Requirement

5.1 RF Exposure

5.1.1 Test Requirement:

CFR 47 Part 1.1310

Limit:

According to FCC Part1.1310: The criteria listed in the following table shall be used to evaluate the environment impact of human exposure to radio frequency (RF) radiation as specified in Part1.1307(b)

TABLE 1—LIMITS FOR MAXIMUM PERMISSIBLE EXPOSURE (MPE)

Frequency range (MHz)	Electric field strength (V/m)	Magnetic field strength (A/m)	Power density (mW/cm²)	Averaging time (minutes)					
	(A) Limits for Occupational/Controlled Exposure								
0.3-3.0	614	1.63	*100	6					
3.0-30	1842/f	4.89/f	*900/f²	6					
30-300	61.4	0.163	1.0	6					
300-1,500			f/300	6					
1,500-100,000			5	6					
	(B) Limits for Genera	al Population/Uncontrolle	d Exposure						
0.3-1.34	614	1.63	*100	30					
1.34-30	824/f	2.19/f	*180/f ²	30					
30-300	27.5	0.073	0.2	30					
300-1,500			f/1500	30					
1,500-100,000			1.0	30					

f = frequency in MHz

According to IEEE C95.3:2002 section 5.5.1.1, The power density S at a point on the axis at a distance d from a transmitting antenna is given by the Friis free-space transmission formula

$$S = \frac{PG}{4\pi d^2}$$

 $S = power density (mW/cm^2)$

P = the net power delivered to the antenna (mW)

G = gain of the antenna in linear scale

d = distance between observation point and center of the radiator (cm)

^{* =} Plane-wave equivalent power density



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5.1.1 IC Radiofrequncy radiation

According to RSS-102 Issue 5, section 2.5.2 Exemption.

RF exposure evaluation is required if the separation distance between the user and the device's radiating element is greater than 20 cm, except when the device operates as follows:

below 20 MHz and the source-based, time-averaged maximum e.i.r.p. of the device is equal to or less than 1 W (adjusted for tune-up tolerance);

at or above 20 MHz and below 48 MHz and the source-based, time-averaged maximum e.i.r.p. of the device is equal to or less than 22.48/f0.5W (adjusted for tune-up tolerance), where f is in MHz;

at or above 48 MHz and below 300 MHz and the source-based, time-averaged maximum e.i.r.p. of the device is equal to or less than 0.6 W (adjusted for tune-up tolerance);

at or above 300 MHz and below 6 GHz and the source-based, time-averaged maximum e.i.r.p. of the device is equal to or less than 1.31 x 10-2 f0.6834 W (adjusted for tune-up tolerance), where f is in MHz:

at or above 6 GHz and the source-based, time-averaged maximum e.i.r.p. of the device is equal to or less than 5 W (adjusted for tune-up tolerance).



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5.1.2 EUT RF Exposure Evaluation

Antenna Gain:

The maximum Gain measured in fully anechoic chamber is 1.585 () in linear scale.

Output Power Into Antenna & RF Exposure Evaluation Distance:

For FCC;

FHSS:

Channel	Frequency (MHz)	Conduct power (including Tune-up tolerance) (dBm)	Conduct powe (mW)	Power Density at R = 20 cm (mW/cm2)	Limit	MPE Ratios	Result
Low	2405	15.9	38.90	0.01227	1	0.01227	PASS
Middle	2442	15.7	37.15	0.01171	1	0.01171	PASS
High	2475	14.4	27.54	0.00868	1	0.00868	PASS

For IC:

FHSS:

Channel	Frequency (MHz)	Conduct power (including Tune-up tolerance) (dBm)	E.I.R.P (dBm)	E.I.R.P (W)	Limit (W)	Result
Low	2405	15.9	17.9	0.061	2.7	PASS
Middle	2442	15.7	17.7	0.058	2.7	PASS
High	2475	14.4	16.4	0.043	2.7	PASS

Note: 1. Refer to report No. HKEM210100000402 for EUT test conducted power value. requirement.



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6 Photographs

Remark: Photos refer to Appendix of HKEM2101000004AT.

- End of the Report -